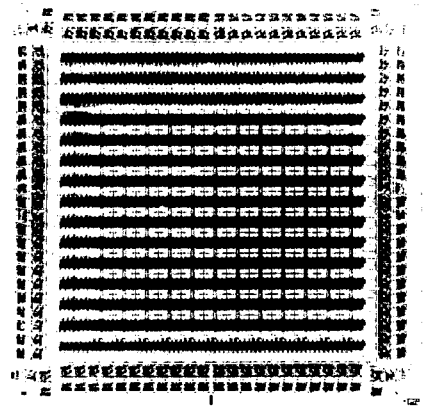
HG61H SERIES

The HG61H series is a master slice CMOS gate array using 2-layer metal interconnect technology. This series has six master chips with wide range of gate count of 448 to 2560, and of I/O terminal count of 54 to 108. These chips can replace not only CMOS logics but also TTL logics thanking for their high speed of 2.0 ns typ and compatibility of input and output buffers at TTL/CMOS level.

LSI design is fully automated by DA (Design Automation) system and custom LSI is developed based on logic diagram and test pattern from customer in a short time and with reasonable cost. EWS (LOGICIAN/DAISY) interface is also available.



■ FEATURES

- **Fast operation**
  Internal gate (2-input NAND, FO=3, AL=3mm) . . . . . 2.0 ns typ
  Input buffer (FO=3, AL=3mm) . . . . . 7.7 ns typ
  Output buffer (C_L=50pF) . . . . . 9.5 ns typ
  Memory access time (HD61MM) . . . . . 40 ns typ
- **Low power dissipation**
  At 10MHz operation (Internal gate) . . . 175μW/gate typ
- **Abundant input and output configuration**
  Allocation of all pins except power supply pins to input/output/input-output common
  Output can be CMOS/open drain/3-state
- **Oscillator, Schmitt input available**
- **Memory on-chip**
  Flexibility of memory capacity and word organization
  Selection of single port/dual port memory
- **Wide operation temperature range**
  −20 to +75°C
- **Wide package selection**
  Especially plastic packages with high pin count DILP64/FPP100
- **Powerful design support**
  User-Defined-Macro
  Test pattern evaluation with fault simulator
  Design support at local Design Center
- **Quick turn around time and reasonable development cost**

■ LINE UP

		△HG61H04	HG61H06	HG61H09	HG61H15	HG61H20	△HG61H25
Gate count		448	660	968	1560	2010	2560
I/O count (max)		54	66	80	84	96	108
RAM on chip		$8^b \times 8^w$	$12^b \times 12^w$	$16^b \times 16^w$	$16^b \times 24^w$	$16^b \times 28^w$	$16^b \times 32^w$
Available I/O count	DP 28	△26	–	○26	–	–	–
	DP 40	△38	○38	○38	○38	○38	△38
	DP 64	△52	○60	○60	○60	○60	△60
	FP 64	△52	△60	–	–	–	–
	FP 80	–	○64	○76	○76	△76	–
	FP 100	–	–	–	–	△94	△96

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△: Under development

■ ABSOLUTE MAXIMUM RATINGS

Item		Symbol	Rating	Unit
Supply Voltage		V_{CC}	−0.3~+6.7	V
Terminal Voltage		V_T	−0.3~V_{CC}+0.3	V
Output Current	per one output	I_O	−8~+8	mA
	total	I_{OT}	−40~+40	mA
Operating Temperature		T_{opr}	−20~+75	°C
Storage Temperature	with Bias	T_{bias}	−20~+85	°C
	without Bias	T_{stg}	−55~+125	°C

Note) Parmanent damage may occur if maximum ratings are exceeded.
Normal operation should be under recommended operating condition, that is

GND ≦ (Vin and/or Vout) ≦ V_{CC}.

If these conditions are exceeded, it could affect reliability of LSI.

* With respect to GND.

■ ELECTRICAL CHARACTERISTICS (V_{CC} = 5V±5%, T_a = −20 to 75°C)

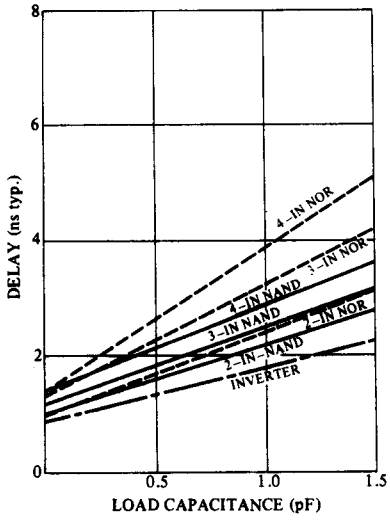
Item		Symbol	Test Conditions	min.	typ.	max.	Unit
Input Voltage (TTL Level)		V_{IHT}		2.2	–	V_{CC}+0.3	V
		V_{ILT}		−0.3	–	0.8	V
Input Voltage (CMOS Level)		V_{IHC}		3.5	–	V_{CC}+0.3	V
		V_{ILC}		−0.3	–	1.5	V
Output Voltage		V_{OH}	I_{OH}=−2mA	3.5	–	–	V
		V_{OL}	I_{OL}=5mA	–	–	0.5	V
Input Leakage Current		I_{LI}		–	–	1	μA
Output Leakage Current		I_{LO}	at high impedance	–	–	1	μA
Gate Delay	Internal	tpd	2 input NAND, FO=3, Aℓ=3mm	–	2.0	–	ns
	Input Buffer	tpd	FO=3, Aℓ=3mm	–	7.7	–	ns
	Output Buffer	tpd	C_L=130pF	–	19	–	ns
Power Dissipation		I_{CC}	Internal 2 input NAND 10MHz	–	35	–	μA/Gate

■ TERMINAL CAPACITANCE (T_a = 25°C, f = 1MHz)

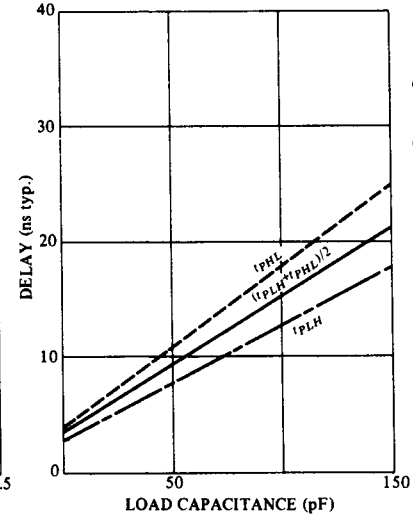
Item	Symbol	Test Conditions	min.	typ.	max.	Unit
Terminal Capacitance	C_T	V_{in}=0V	–	–	12.5	pF

* This parameter is sampled and not 100% tested.

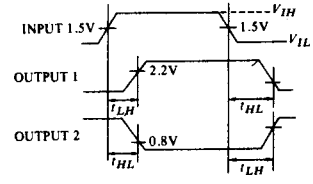
■ INTERNAL GATE DELAY vs LOAD (REFERENCE)



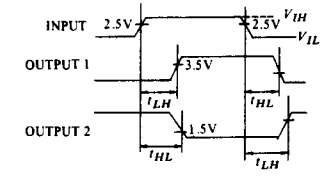
■ OUTPUT BUFFER DELAY vs LOAD (REFERENCE)



■ DELAY TIME



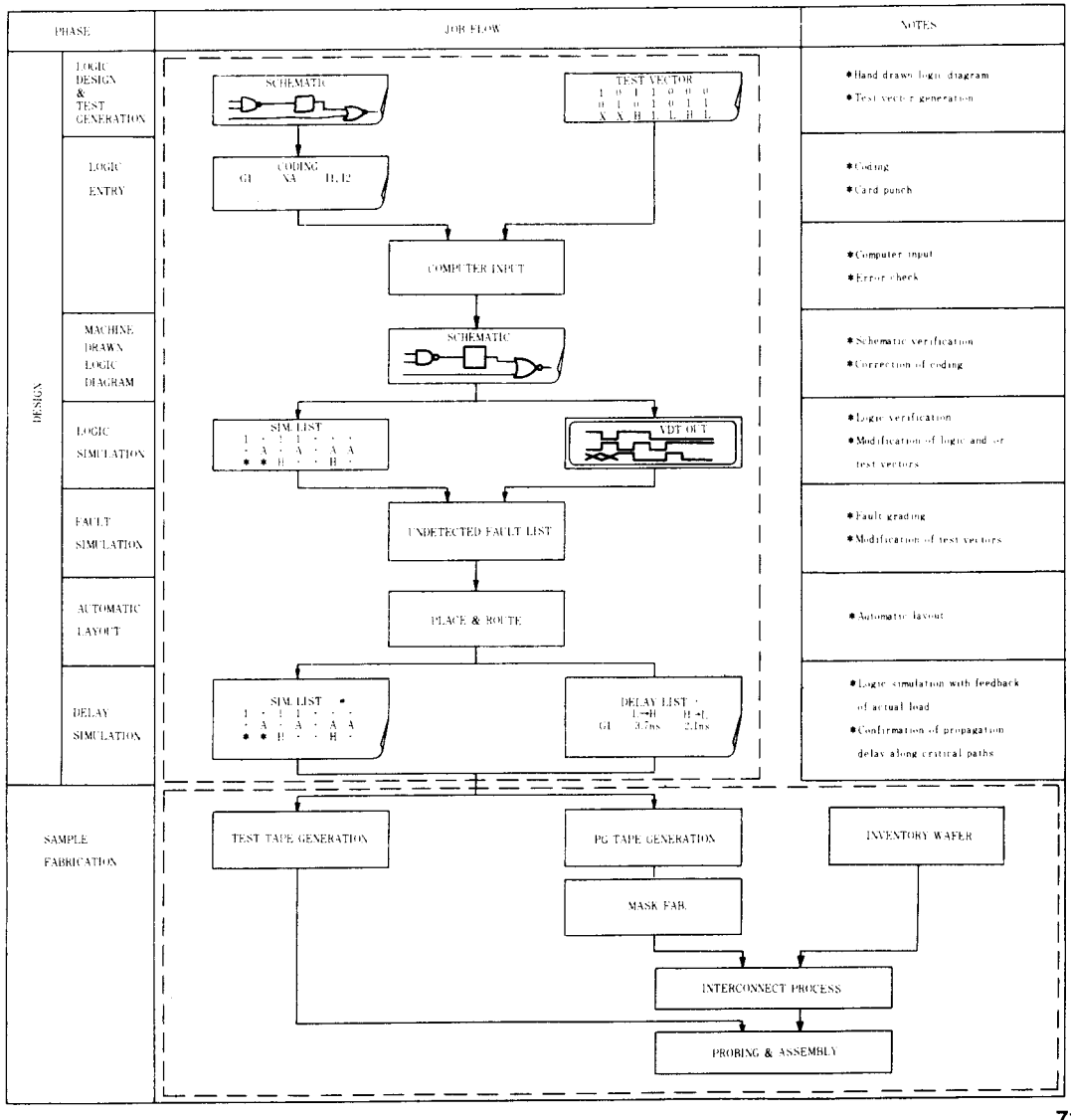
TTL INTERFACE



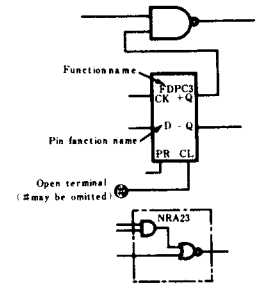
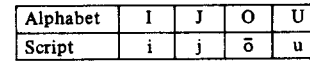
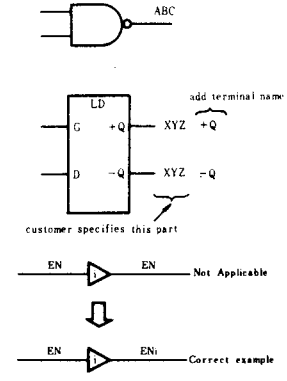
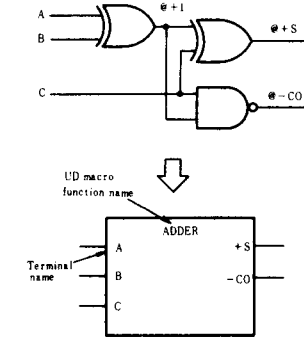
CMOS INTERFACE

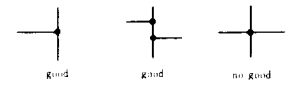
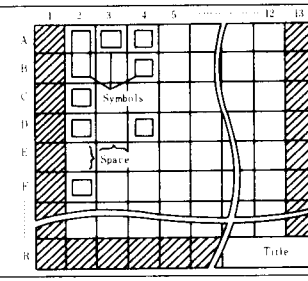
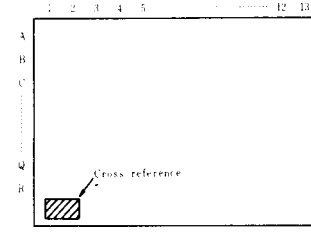
■ DEVELOPMENT FLOW

Development flow of gate arrays is shown below. Logic design and test vectors development are done by users. These are fed to a computer which performs logic simulation. The machine drawn logic diagram is checked by the user. The test pattern is evaluated by the fault simulator then automatic layout is done and precise delay simulation with wiring information. After these design check, PG tape and test tape are generated. Sample production takes very short time because it needs only metal wiring on inventory wafers.
Finished wafers are probed with test vectors from users, then assembled, tested again and shipped.
There are two standard interfaces between a user and Hitachi, Namely:
(1) Logic diagram interface
The user supplies logic diagram and test vectors to Hitachi. Further jobs are done by Hitachi except for some confirmation by the user.
(2) Logic file interface
The user performs simulations by himself at Hitachi Design Center and supplies Hitachi with complete logic file.

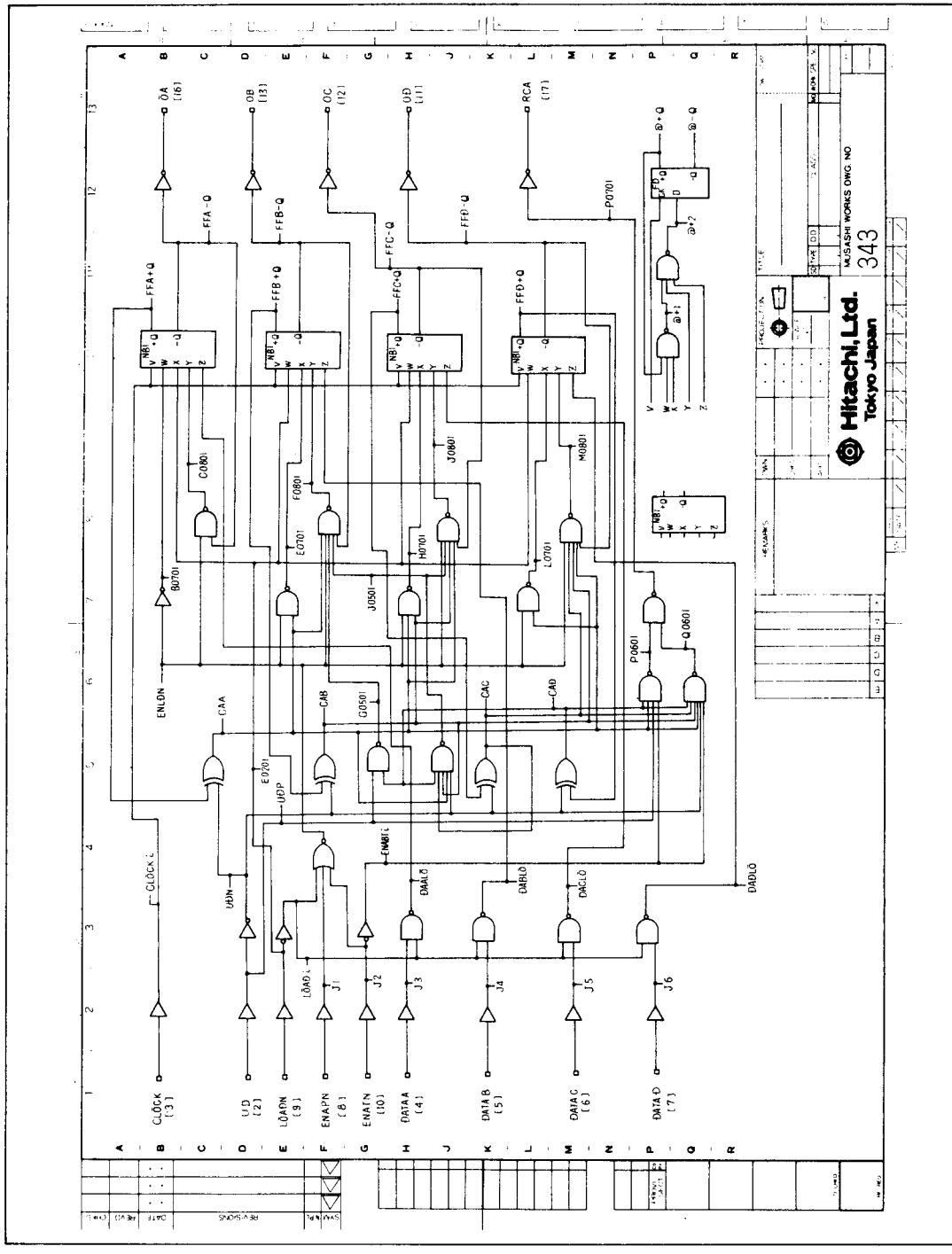


■ HOW TO WRITE LOGIC DIAGRAM

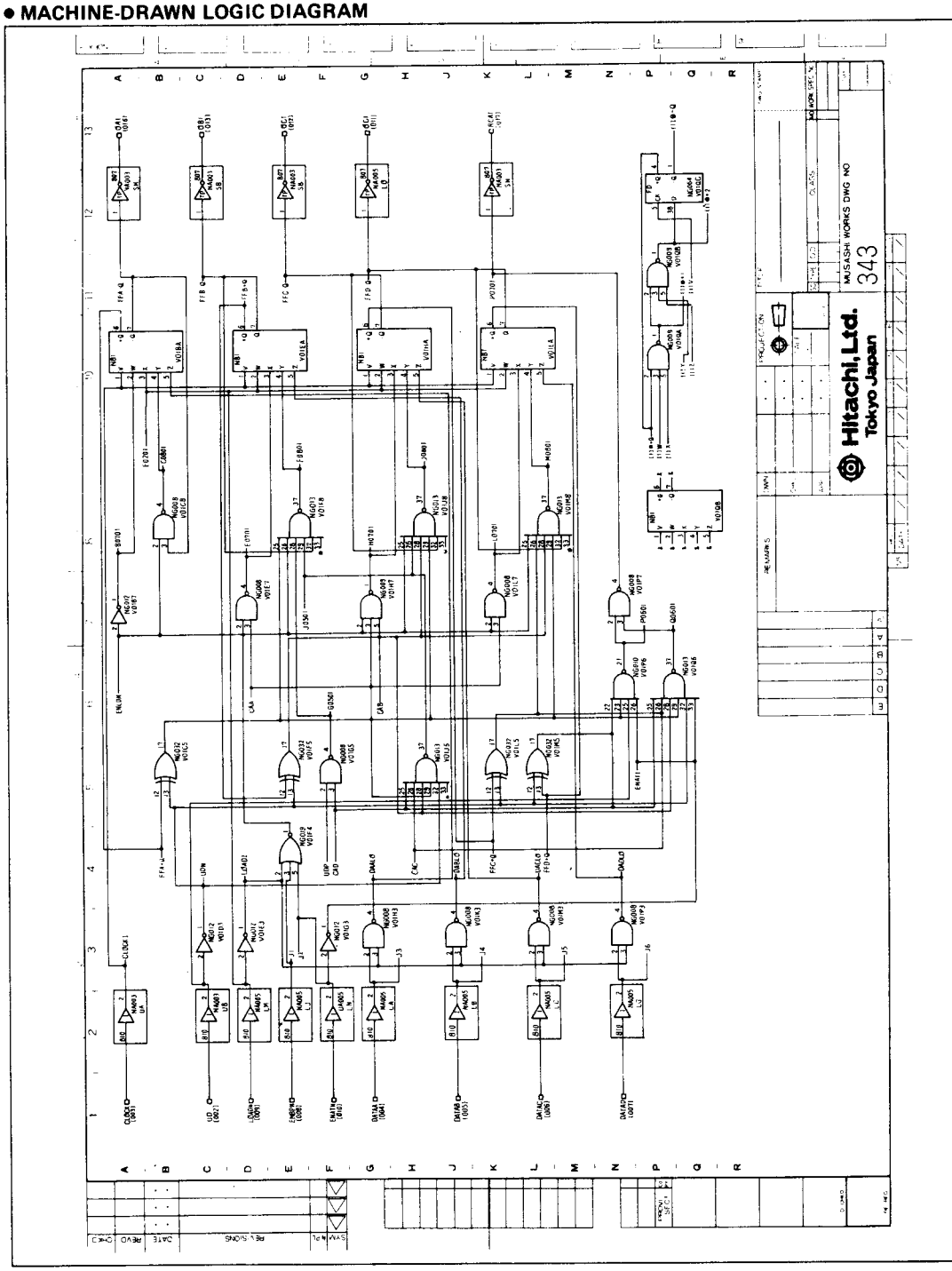
No.	Item	Rules	Examples
1.	Forms	Size A-3 forms supplied by Hitachi	
2.	Logic symbol	(1) Draw logic diagram with exactly the same symbols as shown in Macrocell Library including function name, terminal name and the size. (2) The internal symbol surrounded by dotted line can be omitted but macro function name must be described and the position of terminal can not be changed instead. (3) The template shall be provided. (4) 3-state gate will occupy 2 blocks in the drawing form.	
3.	Characters	(1) 2 to 3mm higher or larger alphabets, +, −, 0 to 9 in total 38 characters. (2) The letters shown in the table must be written as in the bottom column.	
4.	Signal name	(1) Name all pins of LSI within 2 to 5 letters beginning with alphabet (2) For the user's convenience, it is not necessary to name all internal nodes except those which come and go over multi pages. (3) Naming the internal nodes (A) Name macros within 2 to 5 letters beginning with alphabet (B) Memory macros should be named within 3 letters (c) Tri-state gate should be named within 4 letters (d) Output signal name of a macro which has only one output terminal is macro name itself. (e) Output signal names of a macro which has two or more terminals are composite of macro name and terminal name. (f) Combination of location and page number of symbol makes it easy to give name to macros. ex. B0205 (Symbol in page 05, location B02)	
5.	UD-MACRO	The User can define his own macro's. (1) Give name within 4 letters beginning with @ + or @ − to macros which compose UD macro. (2) Give name within 2 letters beginning with alphabet to input terminals. (3) Give function name to UD macros within 5 letters beginning with an alphabet. (4) Define output terminals of UD macro. Then output terminal names will be signal name without @. (5) Now UD-MACRO's can be used in a same way as macros in cell library. Width of UD-MACRO's should be symbol No. A size as shown in the cell library. Height can be determined in proportion to the number of input or output terminals.	

No.	Item	Rules	Examples
5.	Signal line	(1) LSI input/output signal must be shown by and LSI pin number in [ ]. (2) Up to three lines can be connected to one junction point.	
6.	Symbol layout	(1) A signal should flow from left to right. (2) No symbol is allowed to be placed in the first, the 13th column and in the R row. (Shadow area) (3) Keep at least one spacing row every four adjacent occupied rows to keep area for wiring. (4) Keep at least one spacing column in every other column, to assure indication of signal names.	
7.	Cross reference	(1) When signal line extends to another sheet of machine drawing, following informations are indicated automatically. K...15, B-10 →logic location to be connected →page number of logic diagram to be connected →terminal specification of signal destination K . . . . . Sink S . . . . . Source Z . . . . . 3-state output N . . . . . 3-state control	

● MANUALLY-DRAWN LOGIC DIAGRAM



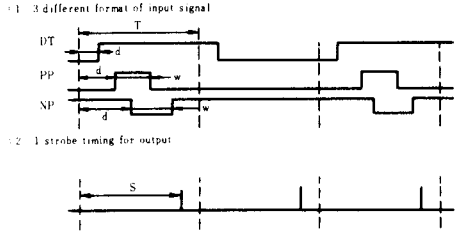
• MACHINE-DRAWN LOGIC DIAGRAM



■ DESTINATION OF TEST VECTORS

1. Limitation of timing:

$T \geq 150$
$d \geq 20$
$W \geq 50$
$S \geq 20$
$T-(d+w) \geq 40$
$T-S \geq 30$



Test Rate		300 ns		
	Timing No.	Format	d(ns)	w(ns)
Input	I_0	DT	–	–
	I_1	DT	20	–
	I_2	PP	50	150
	I_3	NP	70	100
	I_4			
	I_5			
	I_6			
Output	O_1	250 ns		

[Notes] 1. Number of input timing pulses: up to 7.
2. I_0 must be DT format with d = 0.

2. Test Patterns

(1) Specify signal order.
iT = input (TTL Level)
iC = input (CMOS Level)
iT$\overline{O}$ = I/O (TTL Level)
iC$\overline{O}$ = I/O (CMOS Level)
$\overline{O}$T = output
$\overline{O}$Z = 3-state output
$\overline{O}$DN = open drain output

(2) Describe test pattern with following expression. Horizontal axis shows time.

Input	DT format	0,1
	PP format	0,1
	NP format	0,1
Output		H, L, Z, X

(Note 1) In PP and NP format 1 shows an active pulse.
(Note 2) Z . . . . . high impedance
X . . . . . indefinite or masked
(Note 3) Blank can be applied for no signal change.

(3) When the same vectors are repeated, describe like the following next to signal block.
Nesting of LOOP is not allowed.
・ To repeat whole input block

input signal block

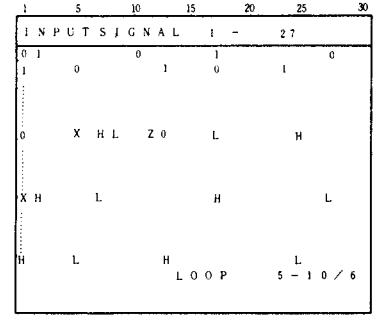
LOOP N
・ To repeat specified columns

input signal block

LOOP S1-e1/N1, S2-e2/N2
N : number of repeat
Sn : start column of repeat
en : end column of repeat

Signal name	I/$\overline{O}$ Format	Pin No.	Timing
INP–1	iT	15	I_1
INP–2	iC	7	I_3
⋮			
BUS–1	iT$\overline{O}$	41	I_0
⋮			
OUT–1	$\overline{O}$T	22	
⋮			

[Notes] 1. Signal name order may be free
2. BUS-1 input timing is I_0 and output strobe timing is O.



[Notes] 1–27 in the line begining with INPUT SIGNAL shows the valid columns in the following data. When these figure are omitted, 1 to 40 columns are regarded valid.

No.	Item	Rules	Examples
3.	Fault detection rate	Fault detection rate of test vectors shall be as high as possible (final target $\geq$ 95%) because it is used in final testing of products. Furthermore, undetected fault by the test vectors is strongly suggested to be checked in the system test at the user's assembly line.	
4.	Limitation of test vectors	(1) Up to 10 sets of test vectors (2) Up to 4000 test cycles after expanding the LOOP's in a set of test vectors (3) Up to 4000 steps in total for all sets of test vectors (LOOP is counted as 1 time.) (4) Up to 100ms test time	

■ EXAMPLE OF LOGIC DESCRIPTION

Schematic description

```
*1
HG61H09B01      TRANS
HG61H09         TYPE      FP80B0
```

Device type, master type package

```
NB1     01Q8    BLOCK     V, W, X, Y, Z
@+1     01Q10   NA        @+Q, W, X
@+2     01Q11   NA        @+1, Y, Z
@       01Q12   FD        V, @+2
                BEND      @+Q, @−Q
```

UD-macro definition

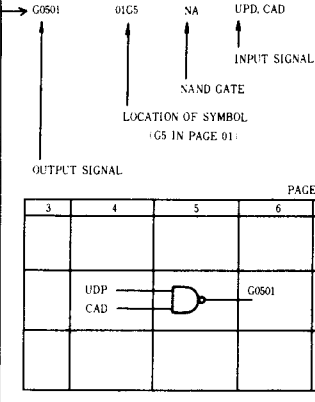
```
UP          02  INPUT
CLOCK       03  INPUT
DATAA       04  INPUT
DATAB       05  INPUT
DATAC       06  INPUT
DATAD       07  INPUT
ENAPN       08  INPUT
LOADN       09  INPUT
ENATN       10  INPUT
OD          11  OUTPUT    OD1
OC          12  OUTPUT    OC1
OB          13  OUTPUT    OB1
OA          16  OUTPUT    OA1
RCA         17  OUTPUT    RCA1
```

Description of I/O terminal including pin assignment.

→ LOADN is an input pin located at pin 9 of the package.

```
CLOCK1  01B2    IT        CLOCK
UDP     01D2    IT        UD
E021    01E2    IT        LOADN
J1      01F2    IT        ENAPN
J2      01G2    IT        ENATN
J3      01H2    IT        DATAA
J4      01K2    IT        DATAB
J5      01M2    IT        DATAC
J6      01P2    IT        DATAD
OA1     01B12   OT        FFA-Q
OB1     01D12   OT        FFB-Q
OC1     01F12   OT        FFC-Q
OD1     01H12   OT        FFD-Q
RCA1    01L12   OT        P0701
UDN     01D3    OT        UDP
LOADI   01E3    NA        E0201
ENATI   01G3    NA        J2
B0701   01B7    NA        ENLDN
DAALO   01H3    NA        J3, LOADI
DABLO   01K3    NA        J4, LOADI
DACLO   01M3    NA        J5, LOADI
DADLO   01P3    NA        J6, LOADI
G0501   01G5    NA        UDP, CAD
E0701   01E7    NA        ENLDN, CAA
L0701   01L7    NA        ENLDN, CAA
P0701   01P7    NA        P0601, Q0601
C0801   01C8    NA        ENLDN, FFA-Q
H0701   01H7    NA        ENLDN, CAA, CAB
P0601   01P6    NA        CAD, CAA, UDP, ENATI
ENLDN   01F4    NR        LOADI, J1, J2
J0501   01J5    NA        CAD, CAC, CAB, CAA, UDN
Q0601   01Q6    NA        CAD, CAC, CAB, CAA, UDN, ENATI
F0801   01F8    NA        CAA, ENLDN, G0501, J0501, FFB-Q
J0801   01J8    NA        ENLDN, J0501, CAB, CAA, FFC-Q
M0801   01M8    NA        ENLDN, CAC, CAB, CAA, FFD-Q
CAA     01C5    EOR       FEA+Q, UDN
CAB     01F5    EOR       FFB+Q, UDN
CAC     01L5    EOR       FFC+Q, UDN
CAD     01M5    EDR       UDN, FFD+Q
FFA     01B10   NB1       CLOCKI, B0701, E0201, C0801, DAALO
FFB     01E10   NB1       CLOCKI, E0201, E0701, F0801, DABLO
FFC     01H10   NB1       CLOCKI, E0201, H0701, J0801, DACLO
FFD     01L10   NB1       CLOCKI, E0201, L0701, M0801, DADLO
                END
```

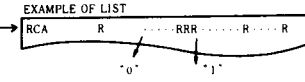
Detail description of logic



Output definition

```
*2
HD61J001    RTSL
CLOCK       OUTDEF  C
UD          OUTDEF  U
LOADN       OUTDEF  L
ENAPN       OUTDEF  P
ENATN       OUTDEF  T
DATAA       OUTDEF  A
DATAB       OUTDEF  B
DATAC       OUTDEF  C
DATAD       OUTDEF  D
RCA         OUTDEF  R
OA          OUTDEF  1
OB          OUTDEF  2
OC          OUTDEF  4
OD          OUTDEF  8
CAA         OUTDEF  A
CAB         OUTDEF  B
CAC         OUTDEF  C
CAD         OUTDEF  D
            INTV    4000 2500
            EDTIME  10000
            EDITIME 0, 0, 4000, 2500
            END
```

Description of signals which you want to look at in the simulation lists.
(Internal signals can be monitored as well.)
Example of list

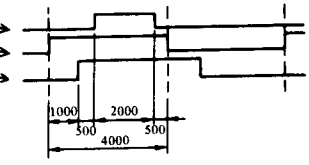


→ Sampling period (ns)
→ Start time in sampling (ns)
→ Maximum simulation step
→ Sampling period and start time for fault simulation.

Timing

```
*4
            STL     4000
CLOCK       CLK     L, 0/1500, 1/2000, 0/500
UD          SIG
LOADN       SIG     1000
ENAPN       SIG
ENATN       SIG
DATAA       SIG
DATAB       SIG
DATAC       SIG
DATAD       SIG
            END
```

→ Test period (x 0.1 ns) per cycle



Test vectors

```
*5
INPUT SIGNAL    1 - 30      ( 1 STEP - 60 STEP)
1           01
01      0
101
10      1 0
10      1 0
01  0
01  0
01  0
0
                LOOP 2
INPUT SIGNAL    1 - 5       ( 61 STEP - 83 STEP)
01010
01
0
0
101
01  0
01  0
01  0
0
                LOOP 1-2/10
                END
```

→ Defines that column 1 to column 30 are valid.

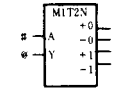
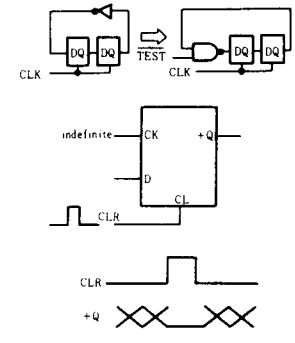
→ The test vectors from column 1 to column 30 are repeated twice.

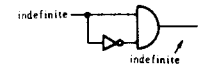
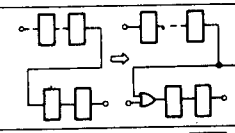
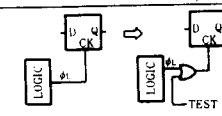
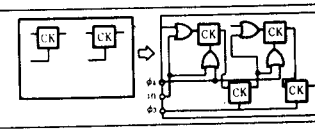
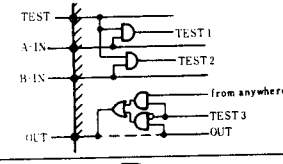
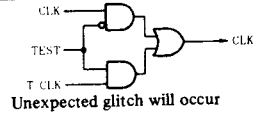
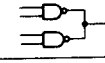
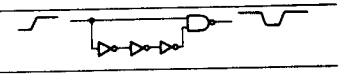
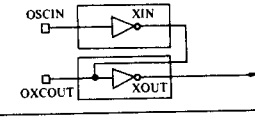
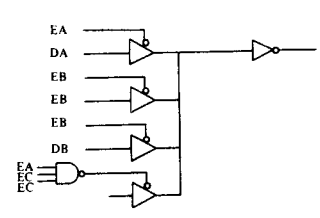
→ Sequential step number (This is just a comment)

→ This expression means that the first two steps are repeated 10 times.

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*6
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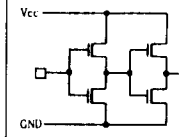
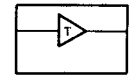
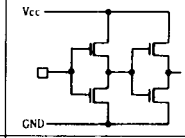
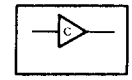
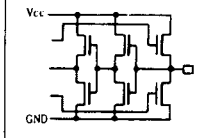
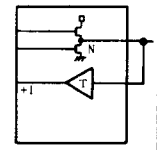
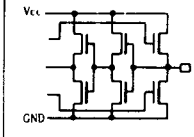
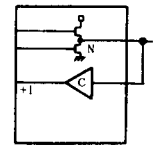
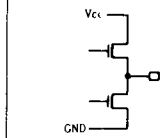
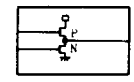
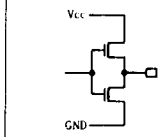
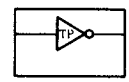
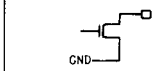
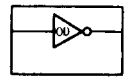
■ NOTES FOR LOGIC DESIGN

No.	Item	Notes	
1.	Utilization	Must be 90% or less in order to place and route successfully. Maximum gate counts for each master chip is shown in the table. (Utilization factor is subject to be a little bit less than the figure in the table when RAM is used.)	Maximum gate counts to be used actually. H04: 400 / H06: 590 / H09: 870 / H15: 1400 / H20: 1800 / H25: 2300
2.	Gate Delay	Gate delay is obtained more accurately after place and route. However rough estimate should also be done using the equations shown right to prevent timing design errors in the earlier design phase. Effective Fan Out is calculated as sum of Normalized Loading Factor of the output node. These equation may contain the design margin a little bit.	$t_{PLH} = t_{OLH} + K_{LH} \cdot C_L$ $t_{PHL} = t_{OHL} + K_{HL} \cdot C_L$ Where, for internal gates $C_L = 0.4 \times EFO$ $EFO = \sum_{Fanout} NLF$ for output buffers $C_L = 130pF$ And the variation is 30% to 220%.
3.	Maximum Fanout	A clock driver, which drives CK inputs of FF's, has a restriction on the number of applicable fanouts, though the other signals have no limitation if lower speed is acceptable.	○ Max. Fanout of CK driver Power Inverter . . . 20 The others . . . . . 10 ○ The other signals 24
4.	Automatic Modification of unconnected inputs of macro	When an input of a macro is left unconnected, the automatic router connects it to either V_{CC} ("1" level) or GND ("0" level). The macrocell list shows which input of each macro will be connected to which level. An input of AND or NAND gates will be connected to V_{CC}, and that of OR or NOR gates to GND, even though these are not indicated in the list. "@" beside an input shows that the input will be connected to V_{CC}, and "#" to GND. It is not allowed to leave an input unconnected dropping "@" nor "#" except the cases of AND, NAND, OR or NOR.	 When inputs are left open, input A will be fixed to "0" input Y will be fixed to "1".
5.	Simultaneous Turn on/off of Output Buffers	The number of output buffers which simultaneously change their output levels must be equal to or less than the figures in the table respectively depending on the prebuffers.	Buffer / Prebuffer: OT / ODN / OZ Inverter: 10 / 8 / 8 2 input NOR: 14 / 10 / 8 3 input NOR: 16 / 12 / 8
6.	Testing	(1) All the logic must be able to be initialized by external inputs. (2) Restriction due to the Simulator. (a) When one or more inputs associated with FF such as CK, CL and PR is indefinite the output is also indefinite. For example, output of FF will not be fixed when CK input is indefinite even if it is quite evident logically that CK input is stable either in high or low level.	

No.	Item	Notes	
		(b) For the given logical variables X, Y, suppose that there is the following relation between them $X = \overline{Y}$ When X or Y is indefinite, both X + Y and X · Y are also indefinite contrary to the theoretical result.	
		(3) It is preferable to split a multistage shift registers and/or counters to provide test signals in the proper positions in order to improve the efficiency of testing.	
		(4) It is preferable to provide test clock in addition to the original clock whose frequency is much lower than other clocks such as a system clock.	
		(5) It is recommended to employ a test circuit that enables memory element to be set and read out by scanning.	
		(6) The figure shows an example of additional test logic to generate several test signals from a single TEST pin, which is helpful when we suffer from the shortage of pins. Another example shown here is to share the output pin to monitor another internal signal.	
		(7) It is very important to do timing design of test logic as well. Is test logic speed OK? Won't unexpected events occur at the transition time from test to normal mode or contrary?	 Unexpected glitch will occur when TEST turns on/off.
7.	Others	(1) As far as a macro is concerned, one signal is prohibited to be employed to multi-input terminals.	
		(2) Output-to-output connection is not allowed except among 3-state buffers.	
		(3) A chopper circuit using gate delay is prohibited.	
		(4) Oscillator circuit should be built as shown. Oscin and OSC OUT pins should be assigned next to the pins which never change their levels, such as V_{CC} and GND.	
		(5) Internal bus lines should be prevented from floating. Dummy 3-state buffer is recommended to be added.	

■ MACROCELL LIBRARY

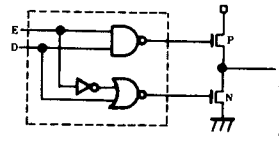
1. I/O BUFFERS

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Input Buffer TTL Level IT		–	–			D1	5.5	0.3	6.5	0.4
Input Buffer CMOS Level IC		–	–			D1	7.5	0.4	7.3	0.3
I/O Buffer TTL Level ITO		–	4.9 3.7			D1	Input See "Input Buffer"		Output See "3-state Buffer"	
I/O Buffer CMOS Level ICO		–	4.9 3.7			D1	Input See "Input Buffer CMOS Level"		Output See "3-state Buffer"	
3-State Buffer OZ		–	4.9 3.7			D1	1.8	0.10	2.5	0.13
OUTPUT OT		–	8			D1	2.8	0.10	3.8	0.14
Open Drain Output ODN		–	3.7			D1	–	–	2.4	0.13

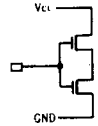
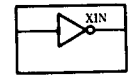
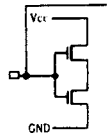
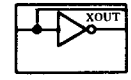
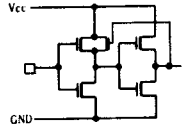
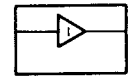
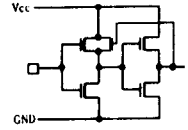
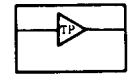
Note) Application of Tri-state buffer

Equivalent circuit

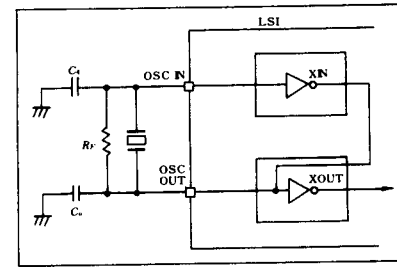




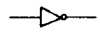
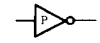
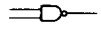
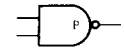
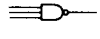
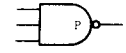
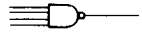
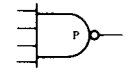
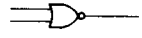
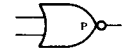
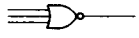
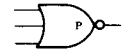
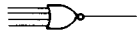
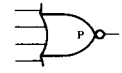
This control circuit has to be built by internal gate

Macrocell: Function / Macro Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level when Open	Symbol	Symbol No.	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) k_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) k_{HL}
OSC In XIN		–	–			D1	6.2	0.8	6.3	0.8
OSC OUT XOUT		–	–			D1	7.9	1.0	5.0	0.9
SCHMITT TTL Level ITS		–	–			D1	8.5	0.4	21.9	0.6
SCHMITT CMOS Level ICS		–	–			D1	10.3	0.5	12.6	0.4

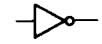
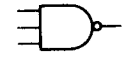
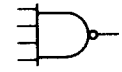
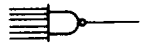
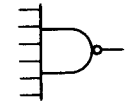
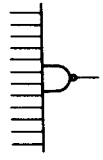
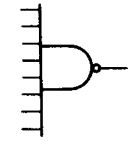
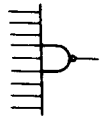
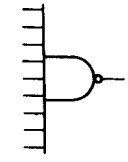
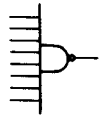
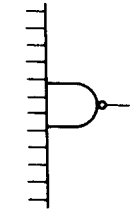
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	OUT	TBD	TBD	TBD	TBD		
H06	IN		12	18	TBD	14	
	OUT		11	17	TBD	13	
H07	IN	9	12	18		14	
	OUT	8	11	17		13	
H15	IN		11	17		13	
	OUT		12	18		14	
H20	IN		11	17		13	16
	OUT		12	18		14	17
H25	IN		TBD	TBD			TBD
	OUT		TBD	TBD			TBD

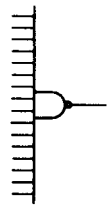
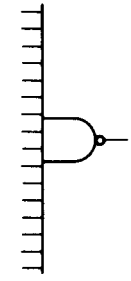
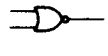
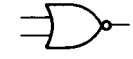
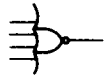
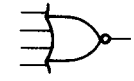
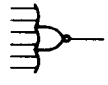
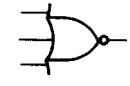
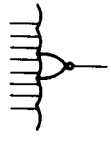
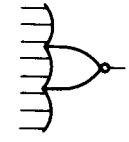
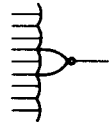
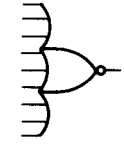


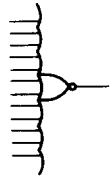
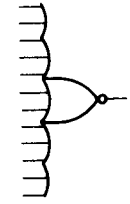
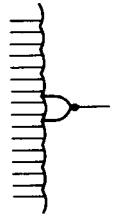
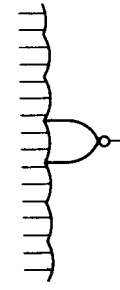
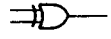
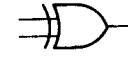
2. POWER GATES

Macrocell: Function / Macro Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level when Open	Symbol	Delay: Symbol No.	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) k_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) k_{HL}
Power inverter NAP		1	1.4	@		–	0.9	0.6	0.3	0.5
Power-2 input NAND NAP		2	1.4			–	1.1	0.6	0.5	0.6
Power-3 input NAND NAP		3	1.4			–	1.3	0.6	0.7	0.8
Power-4 input NAND NAP		4	1.4			–	1.5	0.6	1.1	0.9
Power-2 input NOR NRP		2	1.4			–	1.1	1.1	0.4	0.5
Power-3 input NOR NRP		3	1.4			–	1.7	1.5	0.5	0.5
Power-4 input NOR NRP		4	1.4			–	2.5	2.0	0.6	0.5

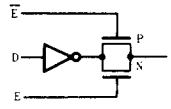
3. GATES

Macrocell: Function / Macro Function Name	Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level when Open	Symbol	Delay: Symbol No.	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) k_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) k_{HL}
Inverter NA		1	1	@		–	1.0	1.1	0.7	0.8
2-Input NAND NA		1	1			–	1.0	1.2	1.0	1.2
3-Input NAND NA		2	1			–	1.0	1.2	1.3	1.5
4-Input NAND NA		2	1			–	1.6	1.2	1.2	1.8
6-Input NAND NA		5	1			–	2.3	1.1	2.6	0.6
8-Input NAND NA		6	1			–	2.5	1.1	3.1	0.6
9-Input NAND NA		7	1			–	2.4	1.1	3.5	0.7
12-Input NAND NA		8	1			–	2.6	1.1	4.1	0.7

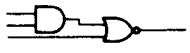
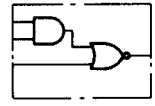
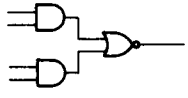
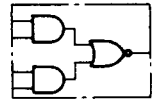
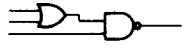
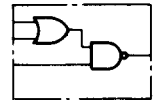
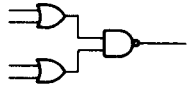
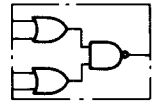
Macrocell: Function / Macro Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level when Open	Symbol	Delay: Symbol No.	Delay: t_{PLH} (ns): t_{OLH}	Delay: t_{PLH} (ns): k_{LH}	Delay: t_{PHL} (ns): t_{OHL}	Delay: t_{PHL} (ns): k_{HL}
16-Input NAND NA		11	1			–	2.7	1.1	4.9	0.8
2-Input NOR NR		1	1			–	1.3	2.1	0.6	0.8
3-Input NOR NR		2	1			–	1.9	3.1	0.7	0.8
4-Input NOR NR		2	1			–	2.1	4.1	0.7	0.8
6-Input NOR NR		5	1			–	3.4	1.1	1.9	0.6
8-Input NOR NR		6	1			–	4.2	1.1	2.0	0.6
9-Input NOR NR		7	1			–	3.8	1.1	2.1	0.6

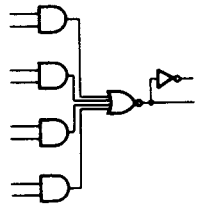
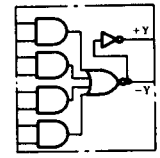
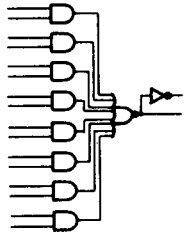
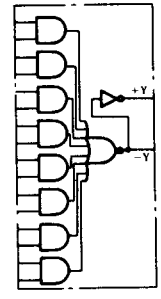
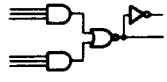
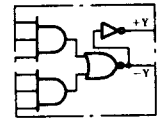
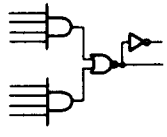
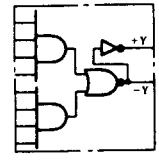
Macrocell: Function / Macro Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level when Open	Symbol	Delay: Symbol No.	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) k_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) k_{HL}
12-Input NOR NR		8	1			–	4.6	1.1	2.2	0.6
16-Input NOR NR		11	1			–	5.3	1.1	2.4	0.6
2-Input EOR EOR		3	1.4			–	2.1	2.1	0.8	1.1

4. 3-STATE GATES

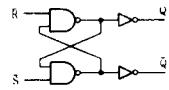
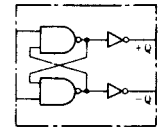
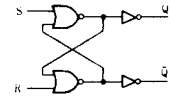
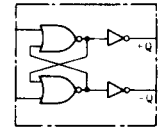
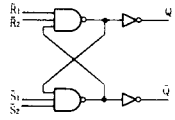
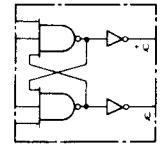
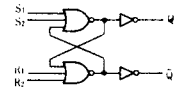
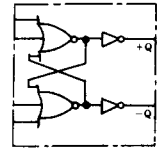
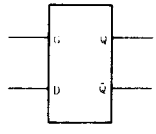
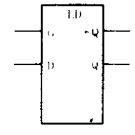
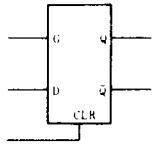
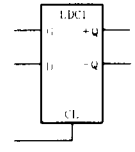
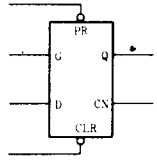
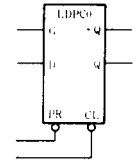
Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) K_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) K_{HL}
3-State Inverter (Internal) NAZ		1	1	# @ @		–	D		1.0	1.0	1.4	1.3
							E/$\overline{E}$		0.8		1.2	
3-State Buffer (Internal) ANZ		3	1.4	# @		–	D		1.0	1.1	1.6	0.6
							$\overline{E}$		1.9		1.6	

5. AND-NOR, OR-NAND GATES

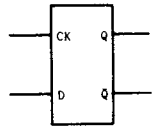
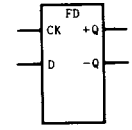
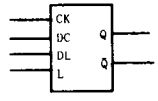
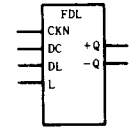
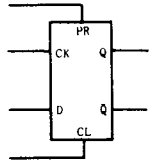
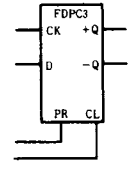
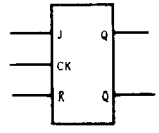
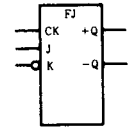
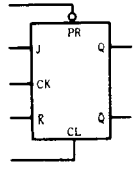
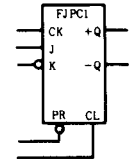
Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) K_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) K_{HL}
2-AND-NOR NRA23		2	1			A1	AND Input		1.7	2.1	0.9	1.1
							NOR Input		1.3		0.9	
2 Wide-2 Input AND-NOR NR2A2		2	1			A1			1.6	1.6	1.1	1.1
2-OR-NAND NAR23		2	1			A1	OR Input		1.6	2.1	0.9	1.1
							NAND Input		1.1		0.9	
2 Wide-2 Input OR-NAND NA2R2		2	1			A1			1.9	2.1	1.0	0.9

Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) K_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) K_{HL}
4 Wide-2 Input AND-NOR NR4A2N		5	1	###		A4		−Y	3.8	2.6	1.7	1.1
								+Y	2.5	1.1	4.3	0.8
8 Wide-2 Input AND-NOR NR8A2N		10	1	###		A5		−Y	2.9	1.1	4.4	1.0
								+Y	4.8	1.1	3.1	0.6
2 Wide-3 Input AND-NOR NR2A3N		4	1			A2		−Y	2.5	1.4	2.0	1.4
								+Y	2.7	1.7	2.6	1.3
2 Wide-4 Input AND-NOR NR2A4N		5	1			A4		−Y	2.5	1.4	2.6	1.8
								+Y	3.5	2.2	2.7	1.2

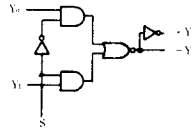
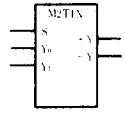
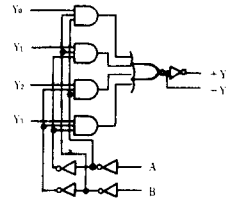
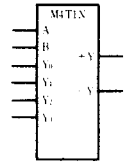
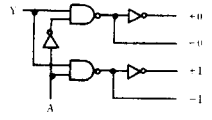
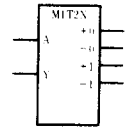
6. LATCHES

Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns)	Delay: K_{LH}	Delay: t_{PHL} (ns)	Delay: K_{HL}
$\overline{RS}$-Latch LRS0		3	1			A3	$\overline{S}$	+Q	2.9	1.1	–	0.6
							$\overline{R}$		1.5		1.9	
							$\overline{S}$	–Q	1.5	1.1	1.9	0.6
							$\overline{R}$		2.9		–	
RS-Latch LRS3		3	1			A3	S	+Q	1.3	1.1	2.4	0.6
							R		–		2.8	
							S	–Q	–	1.1	2.8	0.6
							R		1.3		2.4	
$\overline{R2S}$2- Latch LR2S20		4	1			A4	$\overline{S}$	+Q	3.6	1.1	–	0.6
							$\overline{R}$		2.0		2.1	
							$\overline{S}$	–Q	2.0	1.1	2.1	0.6
							$\overline{R}$		3.6		–	
R2S2- LATCH LR2S23		4	1			A4	S	+Q	1.4	1.1	3.3	0.7
							R		–		4.0	
							S	–Q	–	1.1	4.0	0.7
							R		1.4		3.3	
D-Latch LD		3	1.4 1	@ @		C	G	+Q	1.4	1.1	1.8	0.6
							D		2.0		2.3	
							G	–Q	2.2	1.1	1.8	0.6
							D		2.7		2.4	
D-Latch with CLR LDC1		4	1.4 1 1	@ @ #		C	G	+Q	1.8	2.1	1.9	0.7
							CL		1.6		0.9	
							D		2.3		2.4	
							G	–Q	2.3	1.1	2.4	0.6
							CL		1.3		0.9	
							D		2.8		2.9	
D-Latch with PRE/CLR LDPC0		6	1.4 1 1 1	# @ @ @		C	G	+Q	4.1	1.1	2.1	0.6
							$\overline{PR}$		3.1		–	
							$\overline{CL}$		2.0		1.7	
							D		4.1		3.1	
							G	–Q	3.5	1.1	2.7	0.6
							$\overline{PR}$		2.0		1.7	
							$\overline{CL}$		3.1		–	
							D		4.7		2.7	

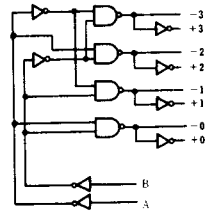
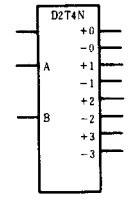
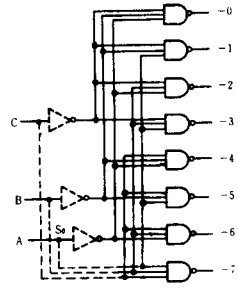
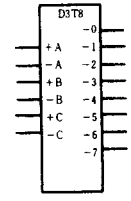
7. FLIP-FLOPS

Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) K_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) K_{HL}
DFF FD		6	1	@ @		C	CK	+Q	2.7	1.1	2.5	0.6
								−Q	2.9	1.1	3.0	0.5
DFF with Load FDL		8	1	@ @ @ #		B4	CK	+Q	2.7	1.1	2.5	0.6
							DL		4.1		4.4	
							CK	−Q	2.9	1.1	3.0	0.5
							DL		4.8		4.4	
DFF with PRE/CLR FDPC3		8	1 1 1.4 1.4	@ @ # #		C	CK	+Q	3.0	2.1	2.8	0.8
							CL		–		0.8	0.8
							PR		2.5		–	–
							CK	−Q	3.8	2.1	3.8	0.8
							CL		1.8		–	–
							PR		–		0.8	0.8
JKFF FJ		8	1.4 1 1	@ @ #		C	CK	+Q	2.4	1.1	3.5	1.0
								−Q	2.8	1.1	3.1	1.0
JKFF with PRE/CLR FJPC1		13	1.4 1 1 1.4 1	@ @ # @ #		C	CK	+Q	5.2	1.1	3.5	0.6
							$\overline{PR}$		4.2		–	
							CL		–		2.5	
							CK	−Q	5.2	1.1	3.5	0.6
							$\overline{PR}$		–		2.5	
							CL		4.2		–	

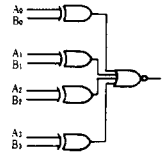
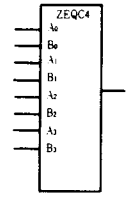
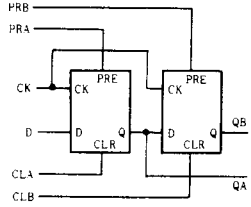
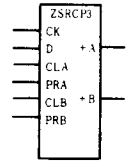
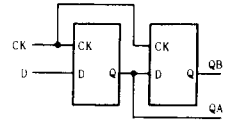
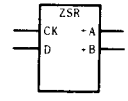
8. MULTIPLEXERS

Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns) / t_{OLH}	Delay: t_{PLH} (ns) / K_{LH}	Delay: t_{PHL} (ns) / t_{OHL}	Delay: t_{PHL} (ns) / K_{HL}
2 to 1 Multiplexer M2T1N		3	1.4 1 1	# # #		B2	Y_0	+Y	2.1	1.1	2.1	0.6
							Y_1		2.1		2.1	
							S		2.6		2.6	
							Y_0	−Y	1.7	2.1	1.7	1.2
							Y_1		1.7		1.7	
							S		2.2		2.2	
4 to 1 Multiplexer M4T1N		9	1	# # # # # #		B4	Y_0	+Y	3.4	1.1	4.6	0.9
							Y_1		3.4		4.6	
							Y_2		3.4		4.6	
							Y_3		3.4		4.6	
							A		4.8		6.0	
							B		4.8		6.0	
							Y_0	−Y	4.0	2.4	2.3	1.4
							Y_1		4.0		2.3	
							Y_2		4.0		2.3	
							Y_3		4.0		2.3	
							A		5.4		3.7	
							B		5.4		3.7	
1 to 2 Demultiplexer M1T2N		4	1.4	# @		B3	Y	+0	1.3	1.1	1.7	0.6
							A		1.8		2.3	
							Y	+1	1.3	1.1	1.7	0.6
							A		1.2		1.7	
							Y	−0	1.5	1.1	0.9	1.1
							A		2.0		1.4	
							Y	−1	1.5	1.1	0.9	1.1
							A		1.5		0.9	

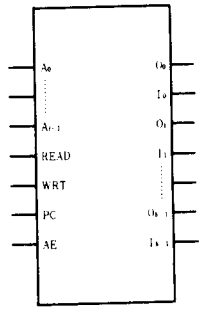
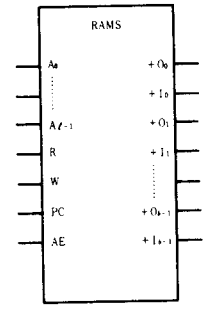
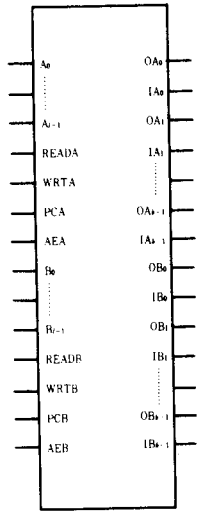
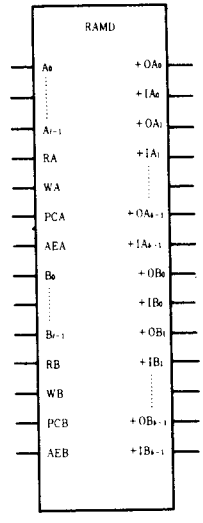
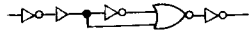
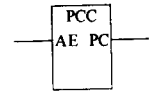
9. DECODERS/ENCODERS

Macrocell: Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Input Name	Output Name	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) K_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) K_{HL}
2-bit Decoder D2T4N		8	1	# # #		B5	A	−0	1.8	1.1	2.0	1.0
							B		1.8		2.0	
							A	−1	2.8	1.1	2.8	1.0
							B		1.8		2.0	
							A	−2	1.8	1.1	2.0	1.0
							B		2.8		2.8	
							A	−3	2.8	1.1	2.8	1.0
							B		2.8		2.8	
							A	+0	2.4	1.1	2.2	0.6
							B		2.4		2.2	
							A	+1	3.2	1.1	3.2	0.6
							B		2.4		2.2	
							A	+2	2.4	1.1	2.2	0.6
							B		3.2		3.2	
							A	+3	3.2	1.1	3.2	0.6
							B		3.2		3.2	
3-bit Decoder D3T8		12	2.2	@ @ @ @ @		B5	A B C	−0 ≀ −7	1.6	1.2	1.0	1.5

10. OTHERS

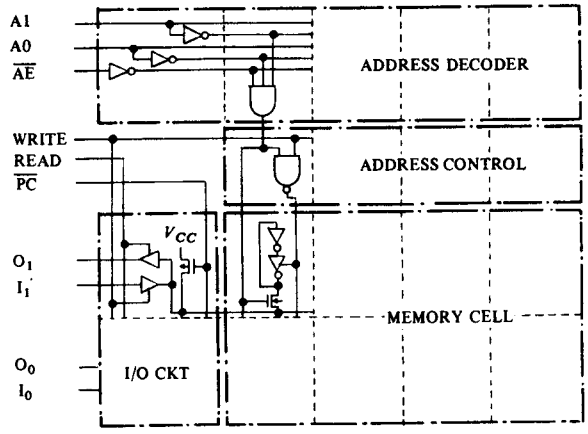
Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Clamp Level When Open	Symbol	Symbol No.	Delay: Input Name	Delay: Output Name	Delay: t_{PLH} (ns) t_{OLH}	Delay: t_{PLH} (ns) K_{LH}	Delay: t_{PHL} (ns) t_{OHL}	Delay: t_{PHL} (ns) K_{HL}
4-bit Equal Comparator ZEQC4		12	1.4	# # # # # # # #		B5	A_0 A_1 A_2 A_3 B_0 B_1 B_2 B_3		4.5	4.2	2.8	0.6
2-bit SR with CLR/PRE ZSRCP3		12	1 1 1.4 1 1.4 1	@ # # # #		B4	CK CLA PRA CK CLB PRB	 +A +B 	4.3 4.1 5.1 4.3 4.1 5.1	 2.1 2.1 	4.1 1.1 – 4.1 1.1 –	0.6 – 0.6 –
2-bit SR ZSR		10	1	@ @		B1	CK	+A +B	3.5 3.5	1.1 1.1	2.9 2.9	0.6 0.6

11. RAM

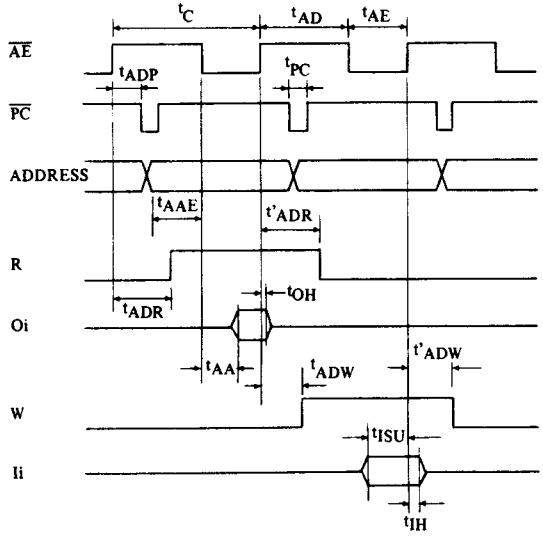
Macrocell: Function / Function Name	Macrocell: Equivalent Circuit	Equivalent Gate Count	Normalized Load Factor	Symbol	Symbol No.	Delay
Single Port RAM b bits/word w=2^{ℓ} word b=2, 4, ..., 16 w=1, 2, ..., 32 RAMS		1.5·b·w + 3b + 6w + 70		 when b−1≧10, the expressions are like follows. b-1 | --8 | 9 | 10 | 11 | 12 | -- Expressions | --8 | 9 | A | B | C | --	A	40 ns
Dual Port RAM b bits/words w=2^{ℓ} words b=2, 4, ..., 16 w=1, 2, ..., 32 RAMD		2·b·w + 7.5b + 8w + 70			A	40 ns
RAM Pre-charge PCC		28	1		B1	

■ EQUIVALENT CIRCUIT OF RAM (Single Port RAM)

The following figure is not exactly the same as the actual circuit.



■ RECOMMENDED TIMING



Unit; ns

	min	typ	max
tc	400	–	30,000
t_{AD}	250	–	–
t_{AE}	150	–	–
t_{ADP}	30	80	160
t_{PC}	10	30	40
t_{AAE}	30	–	–
t_{ADR}	0	–	t_{AD}
t'_{ADR}	0	–	t_{AD}
t_{AA}	20	40	90
t_{OH}	4	10	20
t_{ADW}	0	–	t_{AD}
t'_{ADW}	0	–	t_{AD}
t_{ISU}	30	–	–
t_{IH}	30	–	–

■ FUNCTIONAL TEST FOR ON-CHIP RAM

In order to easily test on-chip RAM, the logic design should be done so as to access the RAM directly outside the chip, for instance in RAM-TEST-MODE.

■ POWER SUPPLY PIN ASSIGNMENT

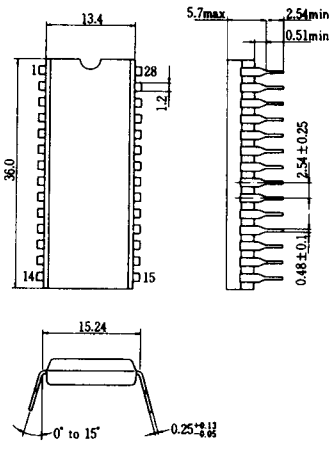
Standard power supply pins are assigned as follows. Additional power supply pins may be needed for the purpose of GND NOISE immunity in case that many output buffers turn on/off simultaneously and/or output-current drains much.

		DP-28	DP-40	DP-64	FP-64	FP-80	FP-100
HG61H04	GND	7	10	16, 48	10, 42		
	V_{CC}	21	30	32, 64	26, 58		
	NC			8, 9, 24, 25 40, 41, 56, 57	1, 2, 19, 20, 33, 34, 51, 52		
HG61H06	GND		10	16, 48		12, 52	
	V_{CC}		30	32, 64		33, 73	
	NC					1, 4, 21, 24, 25, 40, 41, 44, 61, 64, 65, 80	
HG61H09	GND	7	10	16, 48		12, 52	
	V_{CC}	21	30	32, 64		33, 73	
	NC						
HG61H15	GND		10	16, 48		12, 52	
	V_{CC}		30	32, 64		33, 73	
	NC						
HG61H20	GND		10	16, 48		12, 52	
	V_{CC}		30	32, 64		33, 73	
	NC						
HG61H25	GND		10	16, 48			
	V_{CC}		30	32, 64			
	NC						

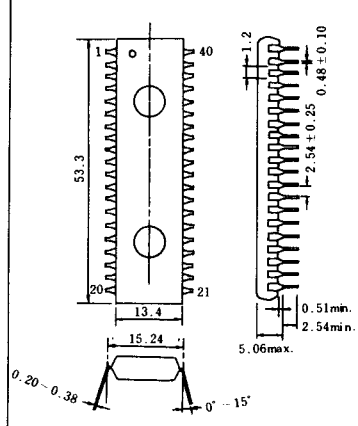
■ PACKAGE OUTLINE

Unit: mm

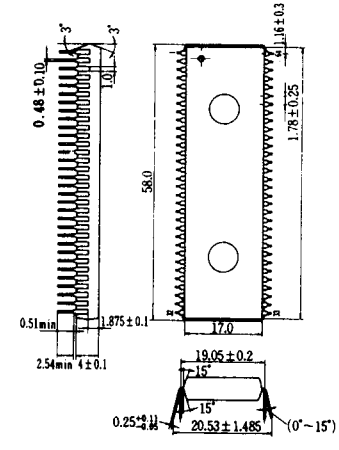
DP28



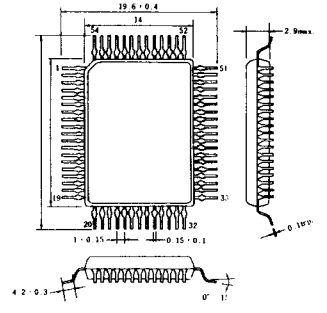
DP40



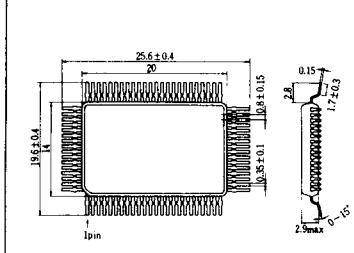
DP64



FP64



FP80



FP100

